

CMS8447B-VB Datasheet

N-Channel 40-V (D-S) MOSFET

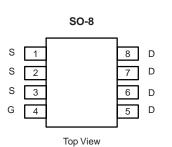
PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^d	Q _g (Typ.)			
40	0.016 at V _{GS} = 10 V	9.5	14.5 nC			
40	0.019 at V _{GS} = 4.5 V	8.5	14.5 110			

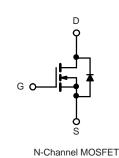
FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Trench Power MOSFET Optimized for "Low Side" Synchronous **Rectifier Operation**
- 100 % R_g and UIS Tested









APPLICATIONS

CCFL Inverter

ABSOLUTE MAXIMUM RATINGS T_A =	25 °C, unless other	erwise noted		
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V_{DS}	60	V	
Gate-Source Voltage	V_{GS}	± 20	v	
	T _C = 25 °C		9.5	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	I _D	8	
Goriandous Brain Guneric (1) = 150 G)	T _A = 25 °C	טי	8 ^{b, c}	
	T _A = 70 °C		6.5 ^{b, c}	A
Pulsed Drain Current	Pulsed Drain Current			A
Continuous Source-Drain Diode Current	T _C = 25 °C	l-	4.2	
Continuous Source-Diain Diode Current	T _A = 25 °C	- I _S	2.1 ^{b, c}	
Avalanche Current	L = 0.1 mH	I _{AS}	15	
Single-Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	11.2	mJ
	T _C = 25 °C		5	
Maximum Power Dissipation	T _C = 70 °C	P _D	3.8	w
Maximum Fower Dissipation	T _A = 25 °C		2.5 ^{b, c}	VV
	T _A = 70 °C]	1.6 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	38	50	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	20	25	- 30/00	

Notes:

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			40		m\//0C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250 \mu\text{A}$		- 6.3		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zoro Coto Voltago Proin Current	I _{DSS}	V _{DS} = 40 V, V _{GS} = 0 V			1 ,,,		
Zero Gate Voltage Drain Current		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	25			Α	
Davis Ossass Os Otata Basista sa	D	V _{GS} = 10 V, I _D = 4.6 A		0.016			
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 4.2 \text{ A}$		0.019		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 4.6 A		20		S	
Dynamic ^b			•	•	•		
Input Capacitance	C _{iss}			1500		pF	
Output Capacitance	C _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		90			
Reverse Transfer Capacitance	C _{rss}			55			
Total Cata Charga	0	$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 4.6 \text{ A}$		21	32		
Total Gate Charge	Q_g			10.5	16		
Gate-Source Charge	Q_gs	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 4.6 \text{ A}$		3.5		nC	
Gate-Drain Charge	Q _{gd}			4.2			
Gate Resistance	R_g	f = 1 MHz		3.3	5	Ω	
Turn-On Delay Time	t _{d(on)}			20	30		
Rise Time	t _r	V_{DD} = 40 V, R_L = 5.4 Ω		150	225	1	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 5.6 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		20	30		
Fall Time	t _f			60	90		
Turn-On Delay Time	t _{d(on)}			10	15	ns	
Rise Time	t _r	$V_{DD} = 40 \text{ V}, R_L = 5.4 \Omega$		15	25]	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 5.6 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		25	40		
Fall Time	t _f			10	15		
Drain-Source Body Diode Characterist	ics			•	•		
Continous Source-Drain Diode Current	I _S	T _C = 25 °C			25	^	
Pulse Diode Forward Current ^a	I _{SM}				45	Α	
Body Diode Voltage	V _{SD}	I _S = 2 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	-		25	50	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			25	50	nC	
Reverse Recovery Fall Time t _a		$I_F = 5.5 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 °\text{C}$		19		ns	
Reverse Recovery Rise Time	t _b			6	İ		

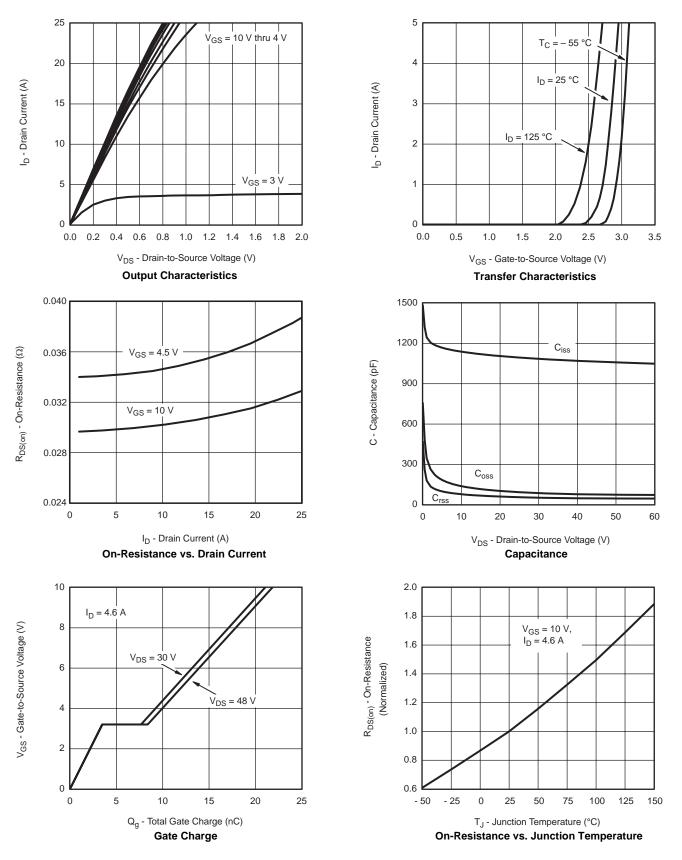
Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

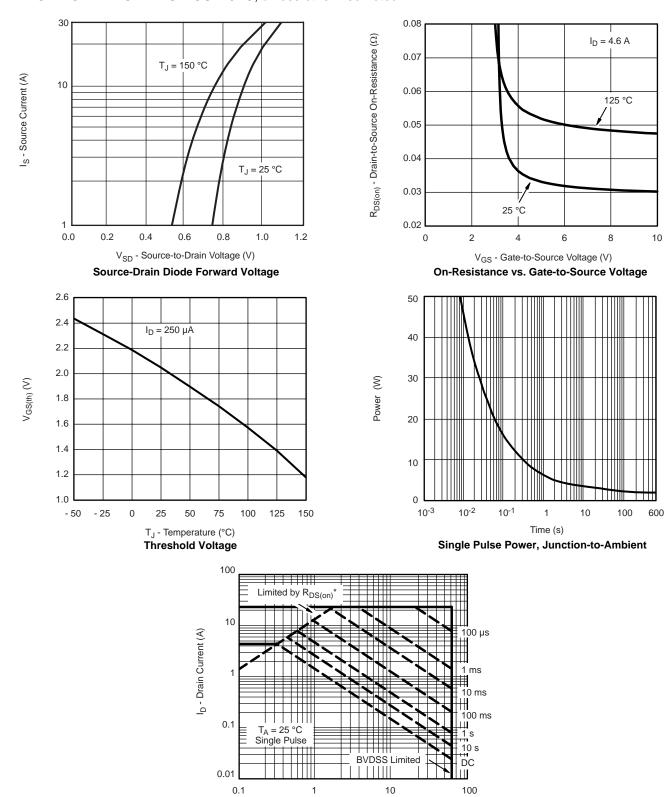
a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$

b. Guaranteed by design, not subject to production testing.







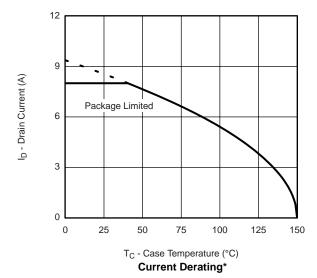


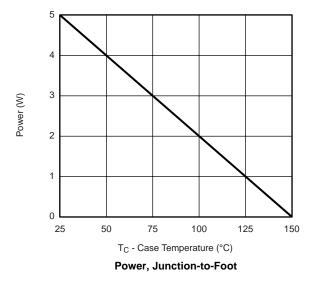
$$\begin{split} & \text{V_{DS} - Drain-to-Source Voltage (V)$} \\ ^* \text{$V_{GS}$ > minimum V_{GS} at which $R_{DS(on)}$ is specified} \\ & \textbf{Safe Operating Area} \end{split}$$

服务热线:400-655-8788

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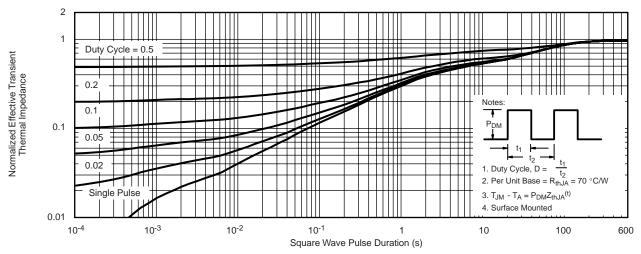




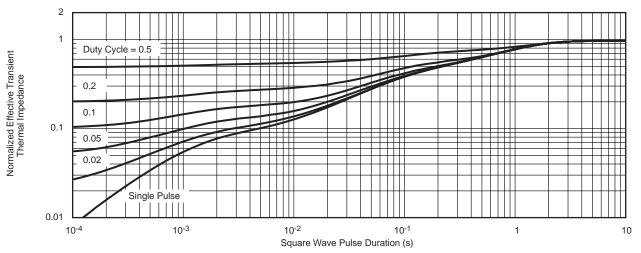


^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit





Normalized Thermal Transient Impedance, Junction-to-Ambient

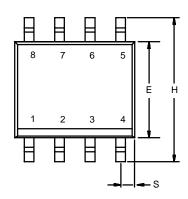


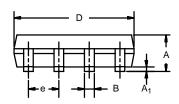
Normalized Thermal Transient Impedance, Junction-to-Foot

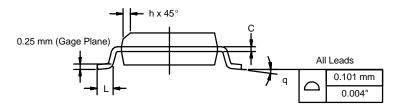


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SOIC (NARROW): 8-LEADJEDEC Part Number: MS-012







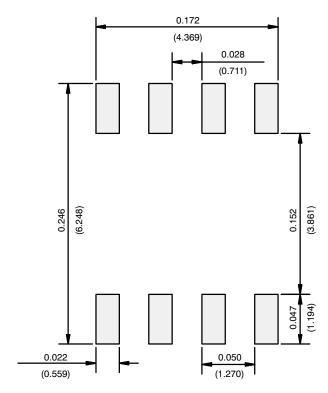
	MILLIMETERS INCHES			HES		
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
Е	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Pay I 11-San-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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